

ICS 77.04
CCS H 17

YS

**NONFERROUS METALS INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

YS/T 1755-2025

**Determination of Total Metal Content and Impurities in
Polycrystalline Silicon - Inductively Coupled Plasma Mass
Spectrometry**

(English Translation)

Issued on: April 10, 2025

Implemented on: November 1, 2025

Issued by: Ministry of Industry and Information Technology

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What this standard covers

This standard specifies a method for determining the total metal content in fluidized bed particulate silicon using inductively coupled plasma mass spectrometry (ICP-MS). This document applies to the determination of total metal content, such as iron, chromium, nickel, copper, sodium, magnesium, aluminum, potassium, calcium, zinc, titanium, molybdenum, tungsten, and cobalt, in fluidized bed particulate silicon. The detection range for each element is 0.05 ng/g to 50 ng/g.

Document data

International classification (ICS): 77.04.

Chinese classification (CCS): H17.

Estimated length of the Chinese original: 776 words.